

KERSMI ELECTRONIC CO.,LTD.
500V N-channel MOSFET

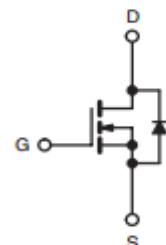
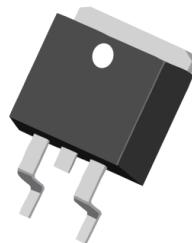
Description

This N-channel MOSFETS use advanced trench technology and design to provide excellent RDS(on) with low gate charge. It can be used in a wide variety of applications.

Features

BVDSS	RDS(on)	ID
500V	0.9Ω	9A

- 1) Low gate charge.
- 2) Green device available.
- 3) Advanced high cell density trench technology for ultra RDS(ON)
- 4) Excellent package for good heat dissipation.


TO-263

Absolute Maximum Ratings $T_c=25^\circ\text{C}$,unless otherwise noted

Symbol	Parameter	Ratings	Units
VDS	Drain-Source Voltage	500	V
VGS	Gate-Source Voltage	± 20	V
ID	Continuous Drain Current-1	9.0	A
	Continuous Drain Current-T=100°C	5.1	
	Pulsed Drain Current2	32	
EAS	Single Pulse Avalanche Energy3	510	mJ
PD	Power Dissipation4	125	W
TJ, TSTG	Operating and Storage Junction Temperature Range	-55 To +150	°C

Thermal Characteristics

Symbol	Parameter	Ratings	Units
R_{JC}	Thermal Resistance ,Junction to Case1	62	°C/W
R_{JA}	Thermal Resistance, Junction to Ambient1	1.0	

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Package Marking and Ordering Information

Part NO.	Marking	Package
KSMB840	KSMB840	TO-263

Electrical Characteristics $T_c=25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{V}_{\text{DS}}=0\text{V}, \text{I}_\text{D}=250\mu\text{A}$	500	—	—	V
I_{DSS}	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=0\text{V}, \text{V}_{\text{GS}}=32\text{V}$	—	—	25	μA
I_{GSS}	Gate-Source Leakage Current	$\text{V}_{\text{DS}}=\pm20\text{V}, \text{V}_{\text{GS}}=0\text{A}$	—	—	±100	nA
On Characteristics						
$\text{V}_{\text{GS}(\text{th})}$	GATE-Source Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_\text{D}=250\mu\text{A}$	2.0	—	4.0	V
$\text{R}_{\text{DS}(\text{ON})}$	Drain-Source On Resistance ²	$\text{V}_{\text{DS}}=10\text{V}, \text{I}_\text{D}=6\text{A}$	—	—	0.9	Ω
		$\text{V}_{\text{DS}}=2.5\text{V}, \text{I}_\text{D}=5\text{A}$	—	—	—	---
G_{FS}	Forward Transconductance	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_\text{D}=12\text{A}$	4.9	—	—	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$\text{V}_{\text{DS}}=15\text{V}, \text{V}_{\text{GS}}=0\text{V},$ $f=1\text{MHz}$	—	1300	—	pF
C_{oss}	Output Capacitance		—	310	—	
C_{rss}	Reverse Transfer Capacitance		—	120	—	
Switching Characteristics						
$\text{t}_{\text{d}(\text{on})}$	Turn-On Delay Time	$\text{V}_{\text{DS}}=20\text{V},$ $\text{V}_{\text{GS}}=10\text{V}, \text{R}_{\text{GEN}}=3.3\Omega$	—	14	—	ns
t_r	Rise Time		—	23	—	ns
$\text{t}_{\text{d}(\text{off})}$	Turn-Off Delay Time		—	49	—	ns
t_f	Fall Time		—	20	—	ns
Q_g	Total Gate Charge	$\text{V}_{\text{GS}}=4.5\text{V}, \text{V}_{\text{DS}}=20\text{V},$ $\text{I}_\text{D}=6\text{A}$	—	—	63	nC
Q_{gs}	Gate-Source Charge		—	—	9.3	nC
Q_{gd}	Gate-Drain "Miller" Charge		—	—	32	nC
Drain-Source Diode Characteristics						
V_{SD}	Source-Drain Diode Forward Voltage ²	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_\text{S}=1\text{A}$	—	—	8.0	V
t_{rr}	Reverse Recovery Time	$\text{I}_\text{F}=7\text{A}, \text{di}/\text{dt}=100\text{A}/\mu\text{s}$	—	460	970	ns
Q_{rr}	Reverse Recovery Charge		—	4.2	8.9	nC

Notes:

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1. The data tested by surface mounted on a 1 inch² FR-4 board 2OZ copper.
2. The data tested by pulse width≤300us,duty cycle≤2%
3. The EAS data shows Max.rating.The test condition is V_{DD}=25v,V_{GS}=10V,L=0.1mH,i_{AS}=17.8A
4. The power dissipation is limited by 150°C junction temperature.

Typical Characteristics $T_J=25^\circ\text{C}$ unless otherwise noted

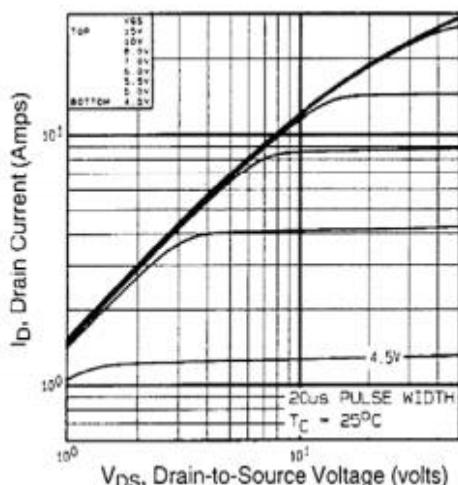


Fig. 1 Typical Output Characteristics,
 $\text{TC} = 25^\circ\text{C}$

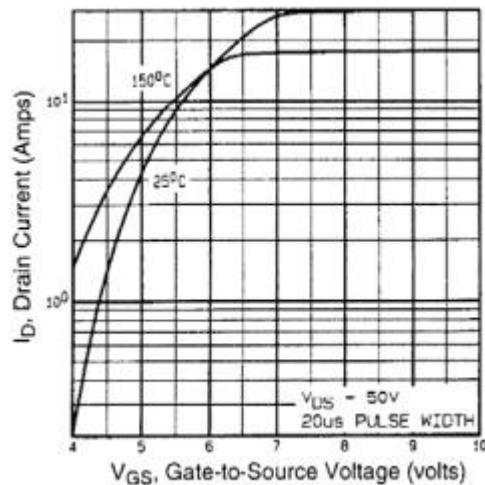


Fig. 2 Typical Transfer Characteristics

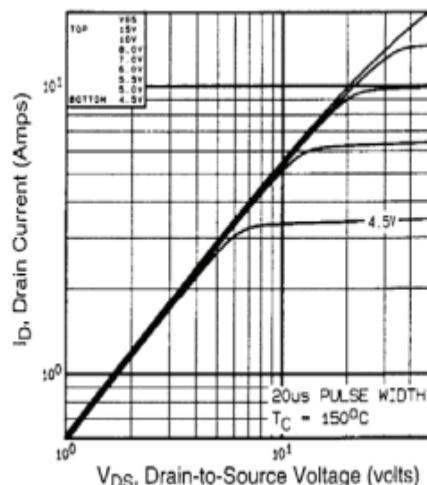


Fig. 3 Typical Output Characteristics,
 $\text{TC} = 150^\circ\text{C}$

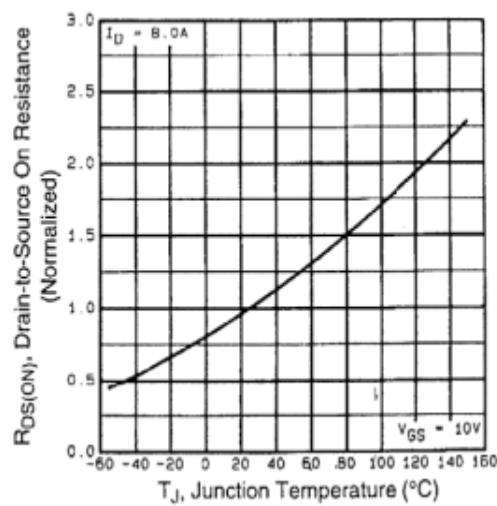


Fig. 4 - Normalized On-Resistance vs.
Temperature

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